

Search Notes

Application/Control No.

10/671,116

Examiner

Sun J. Lin

Applicant(s)/Patent under
Reexamination

SCHIEK, RICHARD

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	19	4/5/2006	JSL
716	21	4/5/2006	JSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	4/5/2006	JSL
IEEE	4/5/2006	JSL
GOOGLE	4/5/2006	JSL